

<b>Notice of References Cited</b>		Application/Control No. 10/564,196	Applicant(s)/Patent Under Reexamination ROCHFORD ET AL.	
		Examiner Sheldon S. Soon	Art Unit 2841	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0185294	12-2002	Shlyakhtichman et al.	174/52.1
*	B	US-6,377,472	04-2002	Fan, Chia-Hao	361/800
*	C	US-4,433,886	02-1984	Cassarly et al.	439/65
*	D	US-2002/0129971	09-2002	Kolb et al.	174/256
*	E	US-2003/0106209	06-2003	FARNWORTH et al.	29/833
*	F	US-6,949,706	09-2005	West, David Owen	174/384
*	G	US-2006/0084289	04-2006	Ziberna, Frank J.	439/067
*	H	US-2004/0075982	04-2004	Kim et al.	361/687
*	I	US-6,320,121	11-2001	Honeycutt et al.	174/384
*	J	US-2004/0240192	12-2004	Seidler, Jack	361/816
*	K	US-5,633,786	05-1997	Matuszewski et al.	361/818
*	L	US-2002/0123265	09-2002	Robinson et al.	439/517
*	M	US-6,136,131	10-2000	Sosnowski, Anthony Michael	156/256

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO 9741716 A1	11-1997	World Intellect	KAUHANIEMI et al.	HO5K 9/00
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.